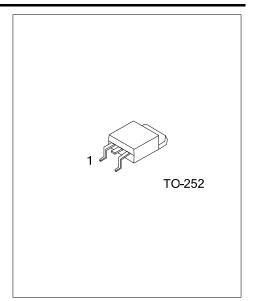
UTT30N08 Preliminary Power MOSFET

# 80V, 30A N-CHANNEL POWER MOSFET

### **■** DESCRIPTION

The UTC **UTT30N08** is an N-channel mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology allows a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

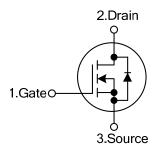
The UTC **UTT30N08** is generally applied in high efficiency switch mode power supplies.



### ■ FEATURES

- \*  $R_{DS(ON)}{<}40m\Omega$  @  $V_{GS}{=}10V,\ I_{D}{=}30A$
- \* High Switching Speed

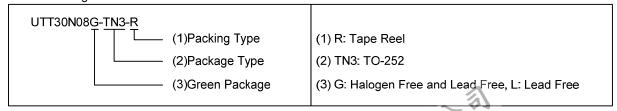
### ■ SYMBOL



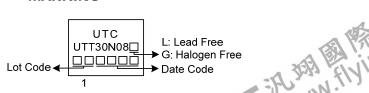
## **■ ORDERING INFORMATION**

Ordering	Doolsone	Pin Assignment			Dooking		
Lead Free	Halogen Free	Package	1	2	3	Packing	
UTT30N08L-TN3-R	UTT30N08G-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



## **■ MARKING**



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## ■ **ABSOLUTE MAXIMUM RATINGS** (T<sub>C</sub>=25°C, unless otherwise specified) (Note 4)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain to Source Voltage		$V_{ t DSS}$	80	V	
Gate-Source Voltage			$V_{GSS}$	±20	V
Drain Current (Note 5)	Continuous	T <sub>C</sub> =25°C	l <sub>D</sub>	30	Α
		T <sub>C</sub> =100°C		18	Α
	Pulsed (Note 2)		$I_{DM}$	90	Α
Avalanche Energy	Single Pulsed (Note 3)		E <sub>AS</sub>	138	mJ
Power Dissipation (T <sub>C</sub> =25°C)		$P_D$	54	W	
Junction Temperature		$T_J$	+150	°C	
Storage Temperature		$T_{STG}$	-55 ~ <b>+</b> 150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating; Pulse width limited by maximum junction temperature.
- 3. L=4mH,  $I_{AS}$ =8.3A.  $V_{DD}$ =50V,  $R_{G}$ =25 $\Omega$ , Starting  $T_{J}$ =25 $^{\circ}$ C
- 4. Drain current limited by maximum junction temperature

## **■ THERMAL DATA**

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	$\theta_{JA}$	110	°C/W	
Junction to Case	θ <sub>JC</sub>	2.3	°C/W	

## **■ ELECTRICAL CHARACTERISTICS**

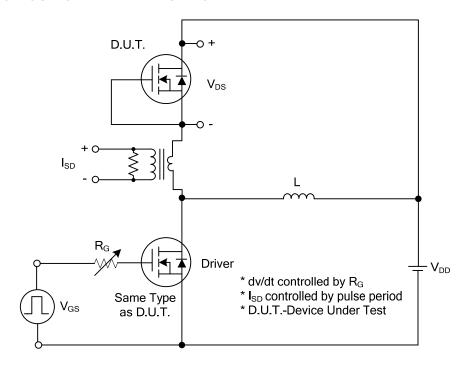
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage		$BV_{DSS}$	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C	80			V	
Drain-Source Leakage Current		$I_{DSS}$	V <sub>DS</sub> =80V, V <sub>GS</sub> =0V,			1	μΑ	
Gate- Source Leakage Current	Forward	I <sub>GSS</sub>	V <sub>GS</sub> =+20V, V <sub>DS</sub> =0V			+100	nA	
	Reverse		V <sub>GS</sub> =-20V , V <sub>DS</sub> =0V			-100	nA	
ON CHARACTERISTICS								
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{GS}=V_{DS}$ , $I_{D}=250\mu A$	1.0		3.0	V	
Static Drain-Source On-State Resistance		D	$V_{GS}$ =10V, $I_D$ =30A			40	mΩ	
		R <sub>DS(ON)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =15A			50	mΩ	
DYNAMIC PARAMETERS								
Input Capacitance		$C_{ISS}$			1810		pF	
Output Capacitance		Coss	V <sub>DS</sub> =25, V <sub>GS</sub> =0V, f=1.0MHz		160		pF	
Reverse Transfer Capacitance		$C_{RSS}$			140		pF	
SWITCHING PARAMETERS								
Total Gate Charge		$Q_{G}$	\\ -CO\\ \\ -10\\   -20A		61		nC	
Gate to Source Charge		$Q_GS$	V <sub>DS</sub> =60V, V <sub>GS</sub> =10V, I <sub>D</sub> =30A (Note 1, 2)		12		nC	
Gate to Drain ("Miller") Charge		$Q_GD$	(Note 1, 2)		16		nC	
Turn-ON Delay Time		$t_{D(ON)}$			16		ns	
Rise Time		$t_R$	$V_{DD}$ =30V, $I_{D}$ =15A, $R_{G}$ =4.7 $\Omega$		18		ns	
Turn-OFF Delay Time		t <sub>D(OFF)</sub>	(Note 1, 2)		50		ns	
Fall-Time		$t_{F}$			25		ns	
<b>SOURCE- DRAIN DIODE RATIN</b>	IGS AND CH	HARACTERIST	rics					
Maximum Body-Diode Continuous Current		I <sub>S</sub>	WE DO			30	Α	
Maximum Body-Diode Pulsed Current		I <sub>SM</sub>	18 108			120	Α	
Drain-Source Diode Forward Voltage		$V_{SD}$	I <sub>SD</sub> =30A, V <sub>GS</sub> =0V			1.4	V	

Notes: 1. Pulse Test: Pulse width≤300µs; Duty Cycle≤2%.

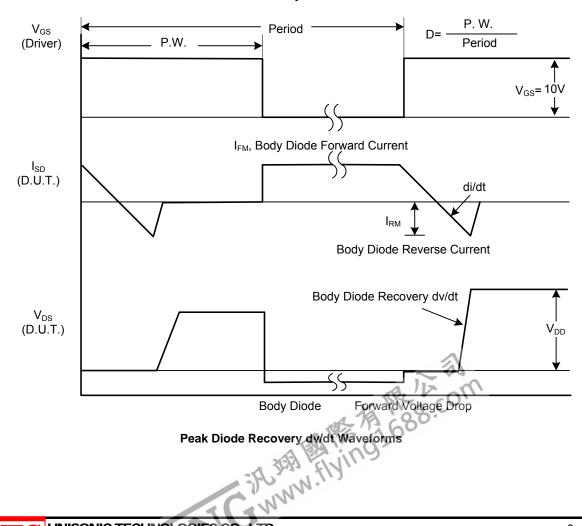
Essentially Independent of Operating Temperature Typical Characteristics



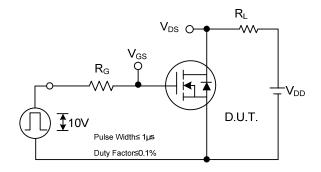
## **TEST CIRCUITS AND WAVEFORMS**

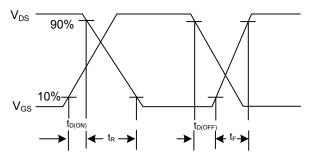


## Peak Diode Recovery dv/dt Test Circuit



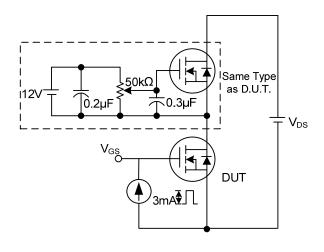
## **TEST CIRCUITS AND WAVEFORMS (Cont.)**

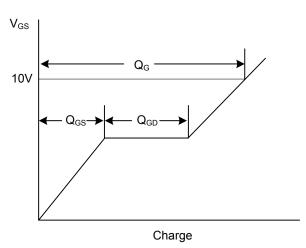




**Switching Test Circuit** 

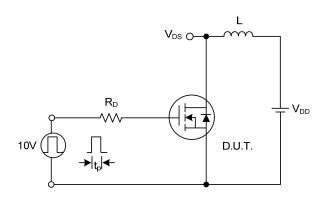
**Switching Waveforms** 

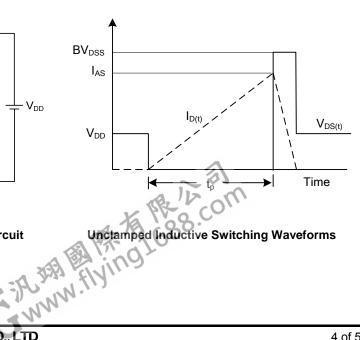




**Gate Charge Test Circuit** 

**Gate Charge Waveform** 





**Unclamped Inductive Switching Test Circuit** 

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